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The guide is published in print and online at **www.microscopy-today.com**. For such a guide to be truly useful, it must be comprehensive. Thus, the editors have assembled an index identifying hundreds of products listed under more than 300 categories.

How to use this Guide:

Print version: (1) Look up the product category in the Products and Services Index.

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- (3) View more complete product descriptions at the company website.
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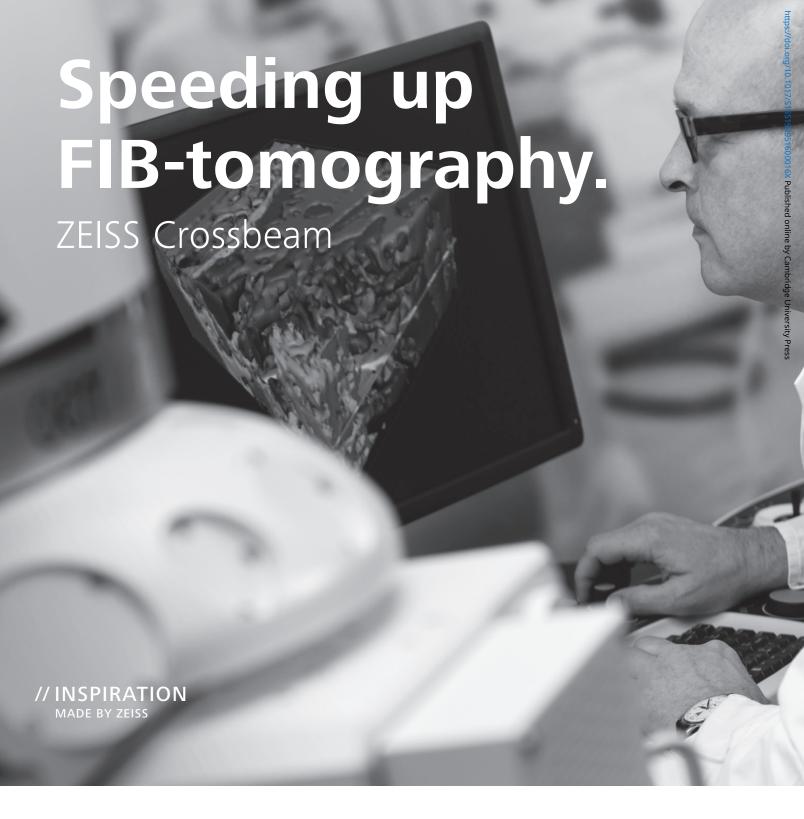
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To companies not listed in this guide:

To list your company and promote your products in our next edition, please contact Kelly Miller at kmiller@mrvica.com or 856-768-9360.

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